Course code								
Type and description	Elective Course							
ECTS credit	1							
Course name	Advanced Characterization Tools in Nanomaterials							
Course name in Polish	Zaawansowane narzędzia do charakteryzacji nanomateriałów							
Language of instruction	English							
Course Level	8 PRK							
Course coordinator	Vignesh Kumaravel							
Course instructors	Vignesh Kumaravel; Lekshmi Gopakumari Satheesh Chandran; Nabil Omri							
Delivery methods and course duration		Lecture	Tutorials	Laboratory	Project	Seminar	Other	Total of teaching hours during the semester
	Contact hours	0	0	0	15	0	0	15
	E-learning	No	No	No	No	No	No	
	Assessment criteria (weightage)	0	-	0	-	0	0,00	
Course objective	Acquisition of knowledge on the basic principles in the characterization of nanomaterials.							
	Acquisition of knowledge on the structural, optical, magnetic, and surface features of nanomaterials. Realizing the significance of advanced characterization tools in biomedical, energy, and environmental applications.							
Learning outcomes	After the course, a Ph.D. student will be able to:							
	1. understand the basic concepts of important characterization techniques in nanotechnology: effects , W4, U4, K1;							
	2. utilize the suitable characterization techniques to analyze the materials in their research: effects W4, U4, K1.							
	3. develop the skills in the safety operation procedures, sample preparation, analysis, and interpretation of the data using various sophisticated instrumentation facilities: effects K1							
	4. apply the acquired knowledge to solve research problems in multidisciplinary fields - W4 and U4.							
Assessment methods	Effects W4 – or	al presentat	tion					
	effects U4, and	K1, – Projed	ct presentation	on				
	The final evaluation is based on:							
	Project Presentation - 100%							

Prerequisites	The basic knowledge in materials science, nanomaterials, and nanotechnology (Graduate in Chemistry, Physics, Biotechnology, Biochemistry, Chemical Engineering, Nanomaterials, Nanoscience, Nanotechnology, Materials Science, and other related disciplines)					
Course content with delivery methods	Introduction to X-ray-based characterizations: (Diffraction, Computed tomography, Fluorescence spectroscopy, and Photoelectron spectroscopy)					
	Introduction to optical characterizations: (UV-visible spectroscopy, Photoluminescence, and surface-enhanced Raman scattering)					
	3.) Analysis of morphology and topology (Scanning electron microscopy, Transmission electron microscopy, and Atomic force microscopy)					
	 Analysis of thermal properties (Thermogravimetric analysis, Differential thermal analysis and Differential scanning calorimetry). 					
	5.) Analysis of magnetic property (VSM)					
	6.) Introduction to surface area analysis					
	Topics of this course will be focused on the utilization of advanced characterization tools in biomedical and environmental applications					
Basic reference materials	 M. Che, J. C. Vedrine, Characterization of Solid Materials and Heterogeneous Catalysts: From Structure to Surface Reactivity, John Wiley & Sons, 2012. D. A. Skoog, F. J. Holter and S. R. Crouch, Principles of Instrumental Analysis, Cengage learning, 2017. 					
	 Ing. VD. Hodoroaba, W. Unger, A. Shard, Characterization of Nanoparticles: Measurement Processes for Nanoparticles, Elsevier, 2019. 					
	4) O. Novais de Oliveira, Jr, F. Marystela, F.L.L. Leite, A.L. Da Róz, Nanocharacterization Techniques, Elsevier, 2017.					
	5) S. Thomas, R. Thomas, A. K. Zachariah, R.K. Mishra, Thermal and Rheological Measurement Techniques for Nanomaterials Characterization, Vol. 3, Elsevier, 2017.					
Other reference materials	1) Z.L Wang (ed), Characterization of Nanophase materials, Wiley-VCH, New York, 2001.					
	2) R.W. Cahn, E.M. Lifshitz, Concise Encyclopaedia of Materials Characterization, Elsevier, 2016.					
	3) C. R. Brundle, C. A. Evans Jr., S. Wilson, Encyclopaedia of Materials Characterization, Butterworth - Heinemann Publishers, 1992.					
	4) R.F. Egerton, Physical Principles of Electron Microscopy: An Introduction to TEM, SEM, and AEM, Springer Nature, 2016.					
	5) D. B. Williams, C. B. Carter, Transmission Electron Microscopy: A Textbook for Materials Science, Vol. 2, Springer Science & Business Media, 1996.					
Average student workload outside the classroom	35 h					
Comments						
Last update	Brak informacji					